Sear	ch N	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/602,146	LEE ET AL.
Examiner	Art Unit
Jordany Núñez	2179

SEARCHED				
Class	Subclass	Date	Examiner	
715	806	12/22/2006	JN	

INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East: USPAT, US PGPUB, EPO, JPO, Derwent, IBM-IDB	12/22/2006	JN
NPL ·	12/22/2006	NL
Consulted with primary examiner, Ba Huynh, AU 2179	12/22/2006	ИС
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